

245903US-2 CONT

IN THE UNITED STATES PATENT & TRADEMARK OFFICE

IN RE APPLICATION OF: :
SHINICH MURAKAWA, ET AL. : GROUP ART UNIT:
SERIAL NO: NEW CONT. APPLN. :
FILED: HEREWITH : EXAMINER:
FOR: APPARATUS AND METHOD :
FOR TESTING ELECTRODE
STRUCTURE FOR THIN DISPLAY...

PRELIMINARY AMENDMENT

COMMISSIONER FOR PATENTS
Alexandria, Virginia 22313

SIR:

Prior to initial examination on the merits, please amend the above-identified application as follows:

Amendments to the Specification begin on page 2 of this paper.

Remarks/Arguments begin on page 3 of this paper.